

High temperature mediated rocksalt to wurtzite phase transformation in cadmium oxide nano-sheets and their theoretical evidences

Arkaprava Das^{1*}, C. P. Saini¹, Deobrat Singh^{2*}, Rajeev Ahuja², Anumeet Kaur³, Sergei Aliukov⁴, D. Shukla⁵ and F. Singh¹

¹Inter University Accelerator Centre, Aruna Asaf Ali Marg, New Delhi-110067, India

²Condensed Matter Theory Group, Department of Physics and Astronomy, Uppsala University, Box 516, 77120, Uppsala, Sweden

³Department of Physics, Guru Nanak Dev University, Amritsar, Punjab-143005, India

⁴Higher School of Economics and management, South Ural state University, Chelyabinsk, 454080, Russia

⁵UGC-DAE Consortium for Scientific Research, University Campus, Khandwa Road, Indore 452017, India

Authors for correspondence: *arkapravadas222@gmail.com

Table 1S: Inter-planner spacing values from XRD pattern

| Sample name | Particle diameter (nm) | 2θ position | Plane | Inter-planner spacing |
|-------------|------------------------|-------------|-------|-----------------------|
| CdO500 | 27 | 33.1 | (101) | 2.70 Å |
| | | 38.4 | (200) | 2.34 Å |
| | | 55.4 | (220) | 1.66 Å |
| CdO700 | 30 | 33.1 | (101) | 2.70 Å |
| | | 38.4 | (200) | 2.34 Å |
| | | 55.4 | (220) | 1.66 Å |
| CdO900 | <i>n.a.</i> | 37.1 | (101) | 2.42 Å |
| | | 48.6 | (102) | 1.87 Å |

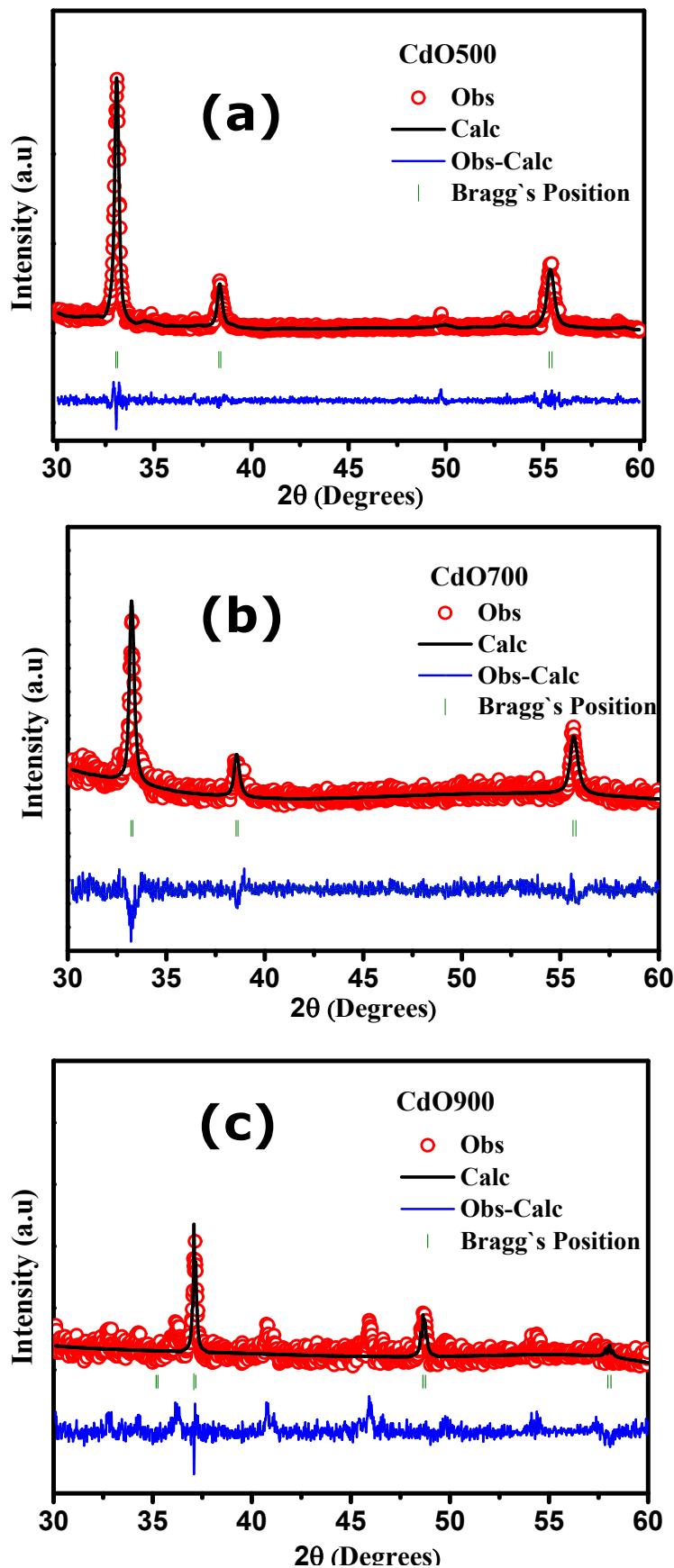


Figure 1S: Rietveld refinement for CdO500, CdO700, CdO900 thin films are shown at (a), (b), (c) respectively

Table 2S: Rietveld refined parameters for various compositions in the system

(a) Results of the Rietveld refinement for CdO500

| Cubic phase with space group $Fm\text{-}3m$ | | | | |
|---|-----|--|-----|------------------------------|
| Ions | x | y | z | B_{iso} (\AA^2) |
| Cd ²⁺ | 0 | 0 | 0 | 1.002 |
| O ²⁻ | 0.5 | 0.5 | 0.5 | 1.075 |
| <i>R</i> -factors | | $R_p = 14.2, R_{w-p} = 19.7, R_{exp} = 16.95, \chi^2 = 1.35$ | | |

(b) Results of the Rietveld refinement for CdO700

| Cubic phase with space group $Fm\text{-}3m$ | | | | |
|---|-----|--|-----|------------------------------|
| Ions | x | y | z | B_{iso} (\AA^2) |
| Cd ²⁺ | 0 | 0 | 0 | 1.450 |
| O ²⁻ | 0.5 | 0.5 | 0.5 | 0.512 |
| <i>R</i> -factors | | $R_p = 17.6, R_{w-p} = 22.8, R_{exp} = 21.18, \chi^2 = 1.16$ | | |

(c) Results of the Rietveld refinement for CdO900

| Hexagonal phase with space group $P\bar{6}3\text{ m c}$ | | | | |
|---|---------|--|---------|------------------------------|
| Ions | x | y | z | B_{iso} (\AA^2) |
| Cd ²⁺ (I) | 0.33330 | 0.66670 | 0.99960 | 1.100 |
| Cd ²⁺ (II) | 0.66670 | 0.33330 | 0.49960 | 1.100 |
| O ²⁻ (I) | 0.33330 | 0.66670 | 0.38530 | 0.886 |
| O ²⁻ (II) | 0.66670 | 0.33330 | 0.88530 | 0.886 |
| <i>R</i> -factors | | $R_p = 24.5, R_{w-p} = 31.9, R_{exp} = 25.43, \chi^2 = 1.57$ | | |

Table 3S: Fitting parameters for O 1s and Cd 3d XPS spectra

| On surface CdO500 (O 1s) | peak position | peak FWHM | peak area | CdO500 2 nd etching peak position | peak FWHM | peak area | CdO500 4 th etching peak position | peak FWHM | peak area |
|---|---------------|-----------|-----------|--|-----------|-----------|--|-----------|-----------|
| Cd(OH) ₂ / CdCO ₃ | 532.07 | 1.74 | 12285 | 531.7 | 2.05 | 5497 | 531.4 | 2.1 | 5540 |
| CdO | 528.9 | 1.12 | 1930 | 529.0 | 0.86 | 6555 | 529.1 | 0.96 | 9903 |
| CdO ₂ | 529.6 | 0.87 | 310.9 | 529.6 | 1.28 | 4707 | 529.7 | 0.77 | 1497 |
| On surface CdO700 (O 1s) | peak position | peak FWHM | peak area | CdO700 2 nd etching peak position | peak FWHM | peak area | CdO700 4 th etching peak position | peak FWHM | peak area |
| Cd(OH) ₂ / CdCO ₃ | 532.08 | 1.76 | 12105 | 531.2 | 2.61 | 8196 | 531 | 3.22 | 12902 |
| CdO | 528.9 | 1.12 | 1940 | 529 | 0.88 | 7707 | 529.1 | 0.82 | 6240 |
| CdO ₂ | 529.6 | 0.88 | 299 | 529.8 | 0.91 | 1498 | 529.7 | 0.58 | 656 |
| On surface CdO900 (O 1s) | peak position | peak FWHM | peak area | CdO900 2 nd etching peak position | peak FWHM | peak area | CdO900 4 th etching peak position | peak FWHM | peak area |
| Cd(OH) ₂ / CdCO ₃ | 531.8 | 1.45 | 8509 | 531.7 | 1.44 | 8303 | 531.8 | 1.40 | 8106 |
| CdO | 530.1 | 1.57 | 16502 | 530.1 | 1.56 | 17301 | 530.2 | 1.59 | 18782 |
| CdO ₂ | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. |
| On surface CdO500 (Cd 3d) | peak position | peak FWHM | peak area | CdO500 2 nd etching peak position | peak FWHM | peak area | CdO500 4 th etching peak position | peak FWHM | peak area |
| CdO | 404.2 | 1.19 | 14519 | 404.4 | 1.0 | 51130 | 404.4 | 1.04 | 52390 |
| CdO ₂ | 405.2 | 1.21 | 6296 | 405.3 | 1.6 | 39863 | 405.3 | 1.6 | 43184 |
| CdCO ₃ / Cd(OH) ₂ | 405.9 | 1.22 | 19820 | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. |
| On surface CdO700 (Cd 3d) | peak position | peak FWHM | peak area | CdO700 2 nd etching peak position | peak FWHM | peak area | CdO700 4 th etching peak position | peak FWHM | peak area |
| CdO | 404.5 | 1.19 | 14519 | 404.4 | 1.07 | 50265 | 404.4 | 1.38 | 46065 |
| CdO ₂ | 405.5 | 1.21 | 6296 | 405.3 | 1.6 | 43076 | 405.5 | 1.37 | 33030 |
| CdCO ₃ / Cd(OH) ₂ | 406.2 | 1.22 | 19820 | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. |
| On surface | peak position | peak FWHM | peak area | CdO900 2 nd | peak FWHM | peak area | CdO900 4 th | peak FWHM | peak area |

| | | | | | | | | | |
|--|-------|------|-------|-----------------------------|------|-------|-----------------------------|------|-------|
| CdO900 (Cd 3d) | | | | etching peak position | | | etching peak position | | |
| CdO | 405.3 | 1.21 | 21319 | 404.8 | 1.40 | 63008 | 404.9 | 1.41 | 66314 |
| CdCO ₃ / Cd(OH) ₂ | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. | n.a. |

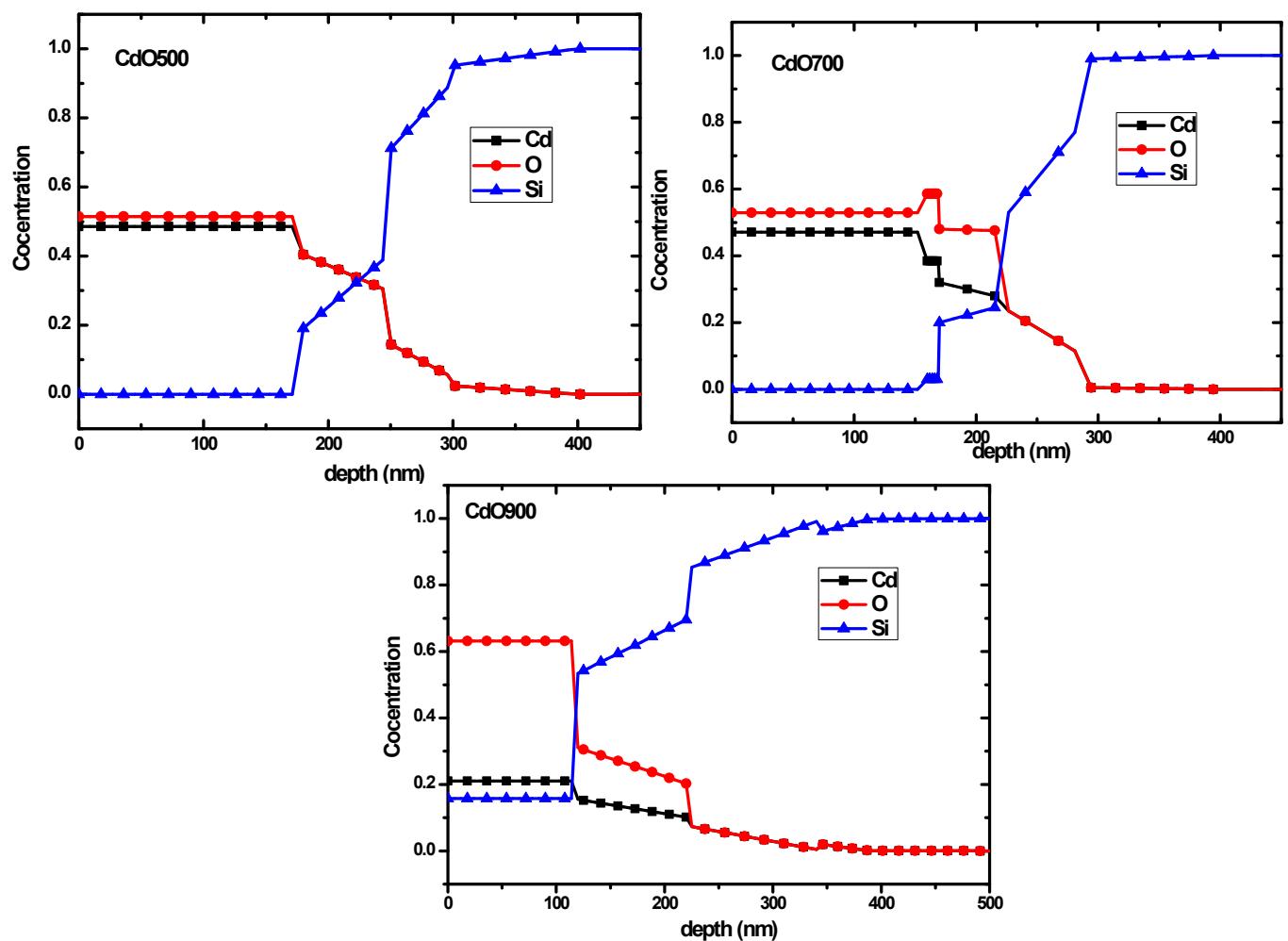


Figure 2S: Depth profiling for CdO500, CdO700, CdO900 thin films

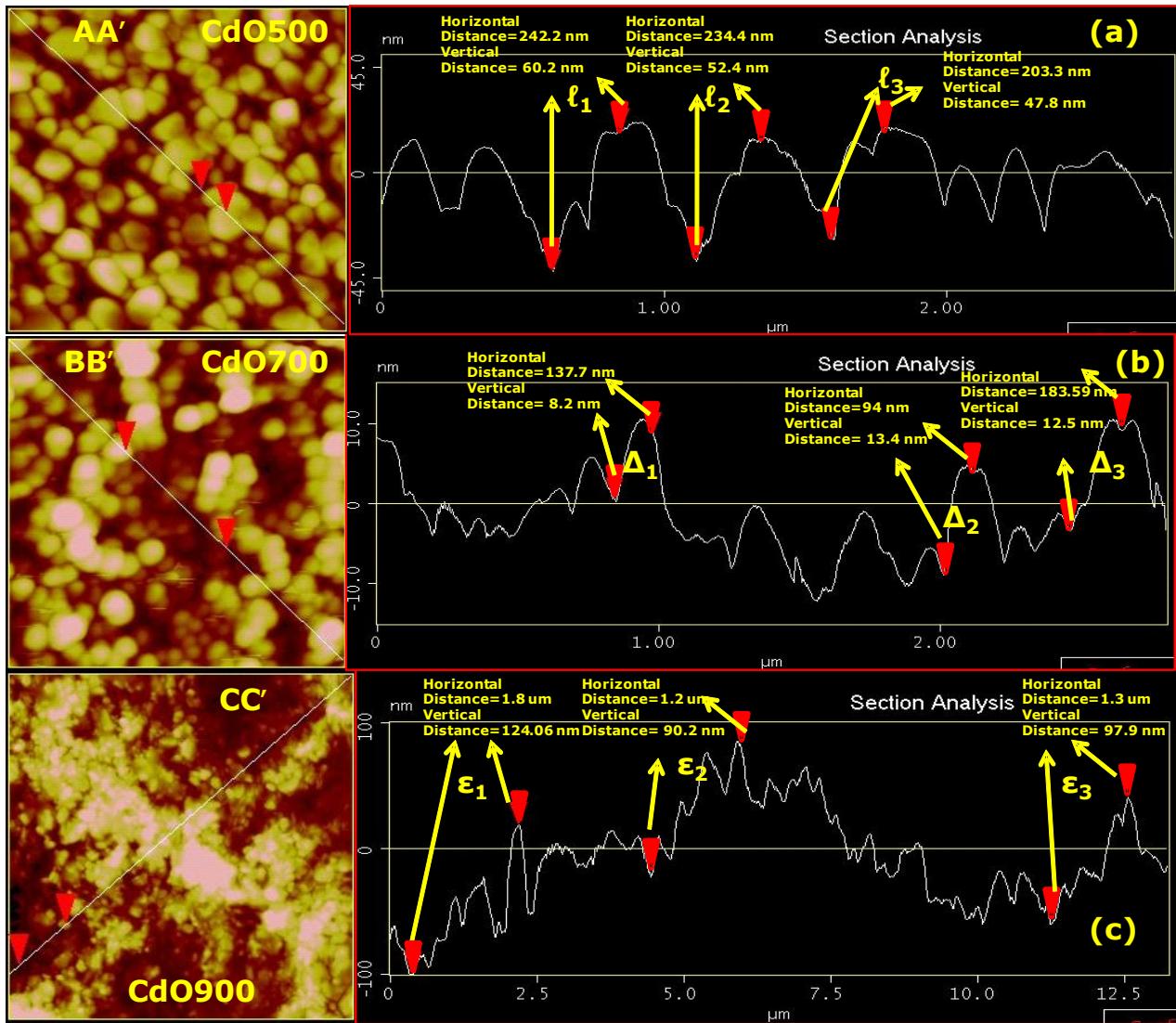


Figure 3S: Section analysis of CdO500, CdO700, CdO900 thin films with nanoscope software

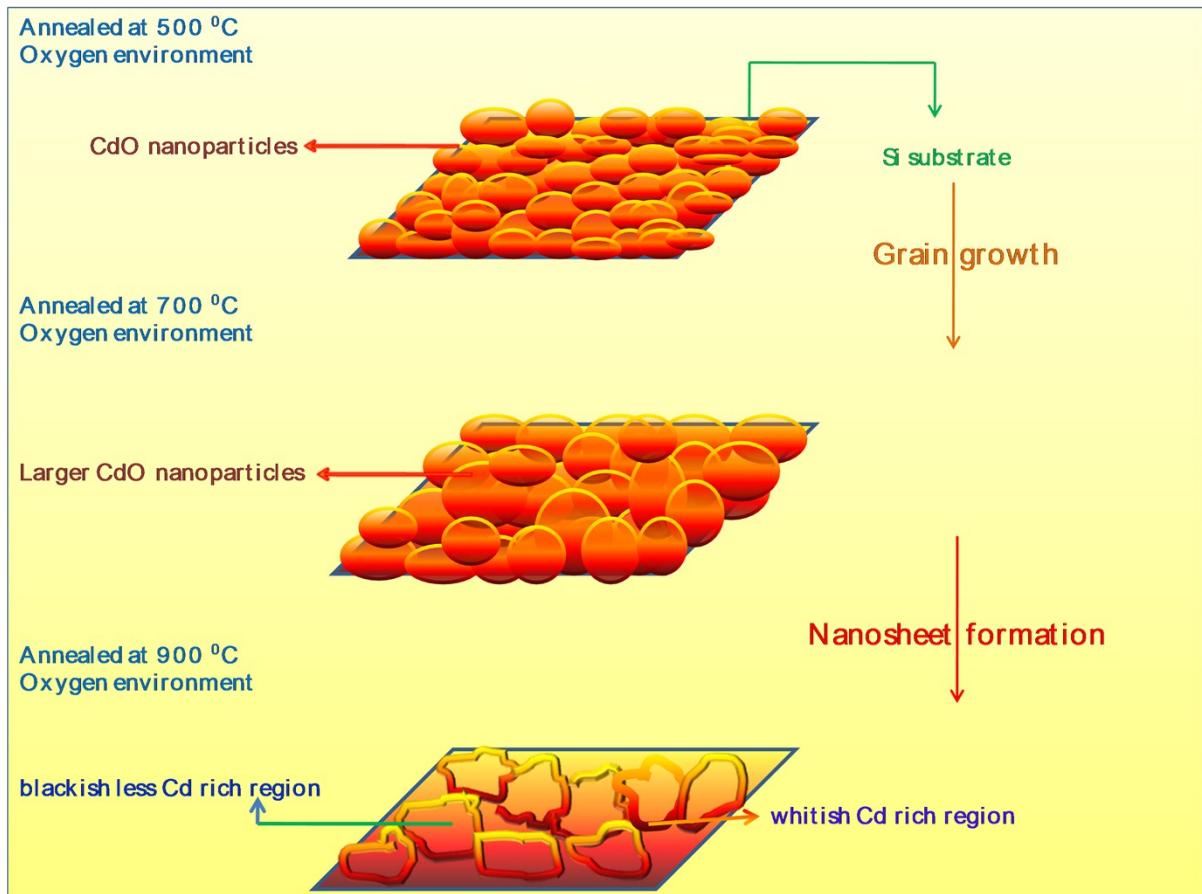


Figure 4S: Schematic illustration of nanosheet formation